

Poster Presentation

## [OLEDp1]OLED poster

Thu. Nov 28, 2019 10:40 AM - 1:10 PM Main Hall (1F)

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10:40 AM - 1:10 PM

### [OLEDp1-14L]Influence of Exciton-Polaron Quenching Occurring at the Interface Mixing Zone on the Operational Lifetime of Solution-Processed OLED

\*NA THI LE<sup>1</sup>, Ja Yeon Lee<sup>1</sup>, Min Chul Suh<sup>1</sup> (1. Department of Information Display, Kyunghee University (Korea))

Keywords:Device lifetime, solution-processed OLEDs, Exciton-Polaron Quenching, Recombination zone

The serious driving voltage rise in HOD could be evidence of EPQ causing device degradation. Strong deterioration was observed when the recombination-zone coincides with the interface-mixing zone, where a higher degree of EPQ occurs. Device lifetime was improved by 8 times as the recombination was confined away from interface mixing zone of solution-processed device.